



1. Introduction

Datasheets are not required to be created to a fixed international standard. This means datasheets must be read and interpreted carefully to ensure that parameter descriptions and values are correctly understood. There are product datasheets for single and dual diodes for differing technology platforms: Silicon diodes (hyperfast, ultrafast etc.), Schottky diodes and Silicon Carbide diodes.

WDN007 looks at the parameters defined and described in WeEn datasheets for Silicon Carbide diodes. The other technology platforms are described in WDN006, "Understanding the diode datasheet".

2. Datasheet product profile

All WeEn's datasheets have the product name and type, revision number and publication date on the first page heading. This is followed by three sections, "General description", "Features and benefits" and "Applications". These sections describe the product to allow the reader to quickly understand its technology, main advantages and uses.

WeEn
WeEn Semiconductors

WNSC2D10650T

Silicon Carbide Diode
Rev.01 - 21 January 2021

Product data sheet

1. General description

Silicon Carbide Schottky diode in a DFN 8*8 plastic package, designed for high frequency switched-mode power supplies.

RoHS **Halogen-Free**
Lead-Free

2. Features and benefits

- Highly stable switching performance
- Extremely fast reverse recovery time
- Superior in efficiency to Silicon Diode alternatives
- Reduced losses in associated MOSFET
- Reduced EMI
- Reduced cooling requirements
- RoHS compliant

3. Applications

- Power factor correction
- Telecom / Server SMPS
- UPS
- PV inverter
- PC Silverbox
- LED / OLED TV
- Motor Drives

Fig. 1. Example of a datasheet product profile (WNSC2D10650T)

The “Quick reference data” section highlights some important parameters for the product found in the main body of the datasheet.

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Values			Unit
Absolute maximum rating						
V_{RRM}	repetitive peak reverse voltage		650			V
$I_{F(AV)}$	average forward current	$\delta = 0.5$; square-wave pulse; $T_c \leq 138$ °C; Fig. 1 ; Fig. 2 ; Fig. 3	10			A
T_j	junction temperature		175			°C
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
V_f	forward voltage	$I_f = 10$ A; $T_j = 25$ °C; Fig. 5	-	1.5	1.7	V
		$I_f = 10$ A; $T_j = 150$ °C; Fig. 5	-	1.8	2.2	V
Dynamic characteristics						
Q_r	recovered charge	$I_f = 10$ A; $di_f/dt = 500$ A/ μ s; $V_R = 400$ V; $T_j = 25$ °C; Fig. 7	-	14	-	nC

Fig. 2. Example of a datasheet product profile (WNSC2D10650T)

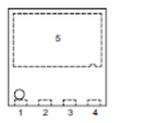
“Pinning information” contains a table and diagram to aid the correct identification of the product’s electrical terminals and package type.

“Ordering information” gives the product’s part number and package version.

The “Marking” section gives data on the labelling printed on the device and data on the packing method.

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	n.c.	not connected		
2	n.c.	not connected		
3	A	anode		
4	A	anode		
5	K	mounting base; connected to cathode		

6. Ordering information

Table 3. Ordering information

Type number	Package name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WNSC2D10650T	DFN8*8	WNSC2D10650TJ	Tape	3000	DFN8X8N	25-Dec-2019

7. Marking

Table 4. Marking codes

Type number	Marking codes
WNSC2D10650T	WNSC2D 10650T

Fig. 3. Example of a datasheet product profile (WNSC2D10650T)

3. Datasheet “Limiting Values”

<p>7. Limiting values</p> <hr/> <p>Table 4. Limiting values <i>In accordance with the Absolute Maximum Rating System (IEC 60134).</i></p>
--

Fig. 4. Example of “Limiting Values” table heading

“Limiting Values” describe the limiting conditions that can be applied by a circuit without risk of damage to the diode, and these limiting values reflect the diode’s capability. These are the absolute maximum ratings for *the operating and environmental conditions* and circuit designers should ensure these are not exceeded. These values may be maximum or minimum. “Limiting” means that the value specified in the table must not be exceeded otherwise the product may malfunction or even be permanently damaged. A limiting value is defined in accordance with the IEC-60134 international standard, known as the “**Absolute Maximum Rating System**”.

3.1 V_{RRM} , V_{RWM} & V_R

<p>8. Limiting values</p> <hr/> <p>Table 5. Limiting values <i>In accordance with the Absolute Maximum Rating System (IEC 60134).</i></p> <table border="1"> <thead> <tr> <th>Symbol</th> <th>Parameter</th> <th>Conditions</th> <th>Values</th> <th>Unit</th> </tr> </thead> <tbody> <tr> <td>V_{RRM}</td> <td>repetitive peak reverse voltage</td> <td></td> <td>650</td> <td>V</td> </tr> <tr> <td>V_{RWM}</td> <td>crest working reverse voltage</td> <td></td> <td>650</td> <td>V</td> </tr> <tr> <td>V_R</td> <td>reverse voltage</td> <td>DC</td> <td>650</td> <td>V</td> </tr> </tbody> </table>	Symbol	Parameter	Conditions	Values	Unit	V_{RRM}	repetitive peak reverse voltage		650	V	V_{RWM}	crest working reverse voltage		650	V	V_R	reverse voltage	DC	650	V
Symbol	Parameter	Conditions	Values	Unit																
V_{RRM}	repetitive peak reverse voltage		650	V																
V_{RWM}	crest working reverse voltage		650	V																
V_R	reverse voltage	DC	650	V																

Fig. 5. Example of diode voltage ratings (WNSC2D10650T)

V_{RRM} is the maximum allowable instantaneous repetitive peak reverse voltage (including transients) that the circuit can apply to the diode. “RRM” describes the voltage as “Reverse”, “Repetitive” and “Maximum”. Similarly, V_{RWM} is the maximum allowable repetitive crest working voltage including transients with “RWM” meaning “Reverse”, “Working” and “Maximum”. V_R is the maximum allowable constant (DC) reverse voltage. Sometimes, V_{RSM} , the maximum allowable non-repetitive peak reverse voltage including all non-repetitive transients is included. If the limiting reverse voltage is exceeded and circuit conditions allow a large reverse avalanche current, then diode damage can result.

The rated values of $V_{RRM(max)}$, $V_{RWM(max)}$ and $V_{R(max)}$ may be applied continuously over the entire operating junction temperature range, provided that the thermal resistance between junction and ambient is low enough to avoid the possibility of thermal runaway.

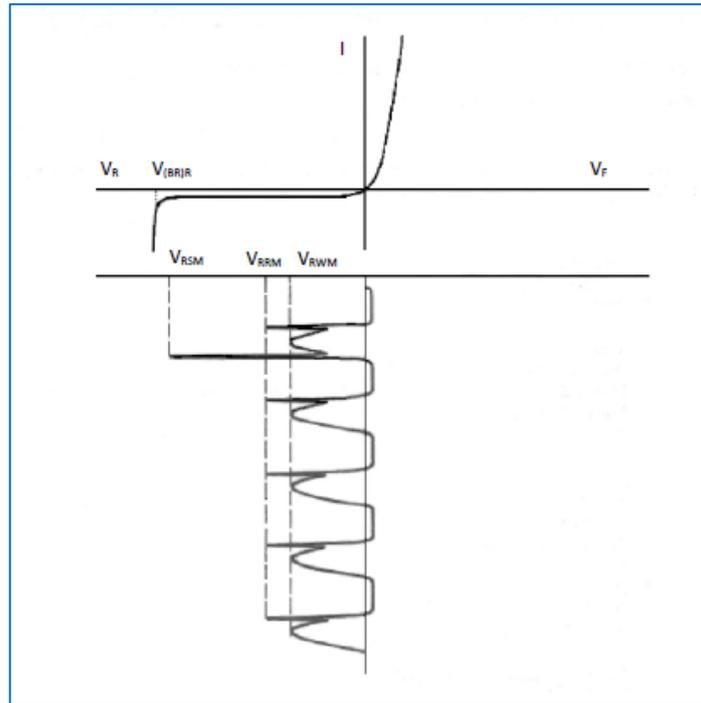


Fig. 6. Diode voltage definitions

3.2 $I_{F(AV)}$ & I_{FRM} [$I_{F(peak)}$]

$I_{F(AV)}$	average forward current	$\delta = 0.5$; square-wave pulse; $T_c \leq 138\text{ }^\circ\text{C}$; Fig. 1 ; Fig. 2 ; Fig. 3	10	A
I_{FRM}	repetitive peak forward current	$\delta = 0.5$; $t_p = 25\text{ }\mu\text{s}$; $T_c \leq 138\text{ }^\circ\text{C}$; square-wave pulse	20	A

Fig. 7. Example of forward current ratings (WNSC2D10650T)

$I_{F(AV)}$ is the value of current for the diode which under steady state conditions results in the rated temperature $T_{j(max)}$ being reached for a given package-related temperature condition. This temperature condition is specified as T_{mb} for “mounting-base” or “tab” type packages (e.g. WNSC2D10650D), T_c for “DFN” type packages (e.g. WNSC2D10650T) and T_h for plastic packages for “heatsink” mounting (e.g. WNSC2D10650X).

$I_{F(AV)}$ is related to the $I_{F(RMS)}$ current parameter by the equations, $I_{F(AV)} = I_{F(RMS)} \times \sqrt{\delta}$, where δ is the duty cycle factor for square wave current.

In WeEn datasheets the I_{FRM} rating is defined such that it is an *additional clarification* of the $I_{F(AV)}$ rating in the condition of continuous current conduction. I_{FRM} is the maximum allowable repetitive peak forward current [$I_{F(peak)}$] including transients which occur every cycle. The junction temperature should not exceed $T_{j(max)}$ during repetitive current transients. The “ I_{FRM} ” rating for square waves with durations no more than 25 μs is relevant in real applications and meaningful to the user.

The I_{FRM} rating and its definition is discussed further in the WDN001, “Understanding I_{FRM} for power diodes”. This parameter is defined differently by various manufacturers.

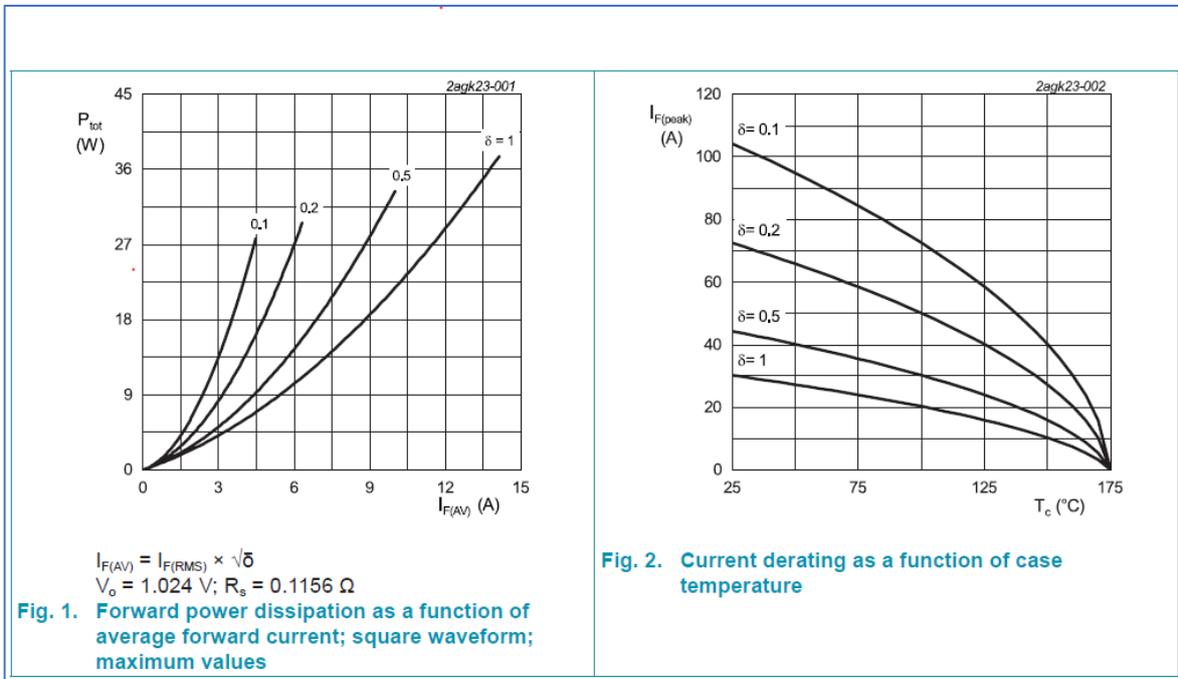


Fig. 8. Examples of P_{tot} vs $I_{F(AV)}$ & $I_{F(peak)}$ vs T_c graphics (WNSC2D10650T)

The current derating graph indicates the reduction of the maximum current recommended for temperatures that may exceed $T_c = 138 \text{ }^\circ\text{C}$ (for this WNSC2D10650T example).

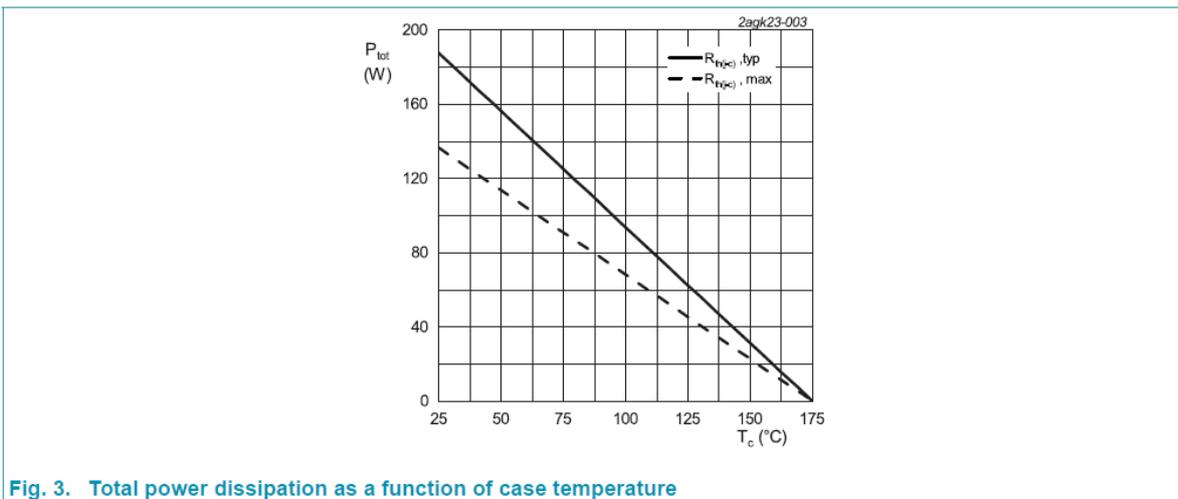


Fig. 9. Example of power dissipation graphic (WNSC2D10650T)

Operating the diode at $I_{F(AV)}$ values above the rated limiting value will lead to exceeding the maximum allowable junction temperature $T_{j(max)}$. This can reduce the long-term reliability of the diode or cause immediate failure.

The average junction temperature rise can be calculated by multiplying the power dissipation at the rated average current by the thermal resistance (e.g. $R_{th(j-mb)}$ or $R_{th(j-h)}$). By subtracting this average junction temperature rise from the maximum allowable temperature, $T_{j(max)}$, the maximum allowable mounting base or heatsink temperature is obtained. This is the value shown in the datasheet text and value indicated on the derating graphics.

It should be remembered that to operate the diode under these conditions means the external heatsinking and cooling arrangements need to dissipate the generated power to the ambient surroundings. *This may mean devices in real applications are derated from the maximum $I_{F(AV)}$ conditions in the datasheet, especially devices surface-mounted on PCBs which usually have high thermal resistance to ambient values.* This derating in real applications holds for all manufacturers of diodes whatever the datasheet specification.

3.3 I_{FSM}

I_{FSM}	non-repetitive peak forward current	$t_p = 10 \text{ ms}; T_{j(init)} = 25 \text{ }^\circ\text{C}; \text{ sine-wave pulse}$	50	A
		$t_p = 10 \text{ } \mu\text{s}; T_{j(init)} = 25 \text{ }^\circ\text{C}; \text{ square-wave pulse}$	450	A

Fig. 10. Example of peak forward current ratings (WNSC2D10650T)

I_{FSM} is the maximum non-repetitive peak forward surge current that may be applied to the diode. It is specified for a single half-sine wave pulse applied to a device at an initial junction temperature of 25 °C before surge, for the duration specified (10ms and 10µs in this case), but may also be specified at 8.3ms to reflect usage at 60 Hz. The shorter the time period of the surge (higher frequency), the higher the I_{FSM} capability. Exceeding the I_{FSM} rating may damage the diode.

3.4 I^2t

I^2t	I^2t for fusing	$t_p = 10 \text{ ms}; T_{j(init)} = 25 \text{ }^\circ\text{C}; \text{ sine-wave pulse}$	12.5	A^2s
--------	-------------------	---	------	----------------------

Fig. 11. Example of I^2t for fusing rating (WNSC2D10650T)

The rating of this parameter serves to determine the diode's *short circuit* current capability i.e. its capability to retain its electrical and mechanical property integrity after surge stress. This rating is numerically linked with the I_{FSM} rating by the equation:

$$I^2t = (I_{FSM}^2/2) \times t_p \equiv I_{FSM}^2/200$$

This is for $t_p = 10ms$ (50Hz half-sine duration) fusing time.

The same value for I^2t is calculated when $t_p = 8.33ms$ (60Hz half-sine duration) using the corresponding I_{FSM} rating at 60Hz.

3.5 T_{stg} and T_j

T_{stg}	storage temperature		-55 to 175	°C
T_j	junction temperature		175	°C

Fig. 12. Example of temperature ratings (WNSC2D10650T)

T_{stg} gives the values for the range of temperature allowable for storage (dispatching, handling, warehousing) of the diode. $T_{j(max)}$ is the maximum operating junction temperature for the diode in the on-state or blocking state. Although the junction temperature may transiently exceed $T_{j(max)}$ without damage, (e.g. during exceptional, brief, non-repetitive overload, or fault conditions), for repetitive operation the peak junction temperature must remain below the absolute maximum rating.

4. Datasheet “Characteristics”

“Characteristics” are the inherent measurable parameters for the diode and are often stated with minimum or maximum values or both. Sometimes typical values are given. The limits define a range of values for the diode’s inherent parameter characteristics. These values are useful to the designer for optimizing the circuit and ensuring reliable operation.

4.1 Thermal characteristics, R_{th} and Z_{th}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	Fig. 4	-	0.8	1.1	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient free air	in free air	-	50	-	K/W

Fig. 13. Example of thermal characteristics (WNSC2D10650T)

Maximum steady-state thermal resistance values are given in the datasheet and are used to specify the diode’s current and power ratings. As previously mentioned, the average junction temperature rise for a given power dissipation is the mathematical product of the average dissipation and the thermal resistance.

A typical value of junction to ambient thermal resistance is given which assumes that through-hole leaded devices are mounted vertically on a PCB in free air. The value for surface mount packages is for a device soldered to a pad area on a given PCB material.

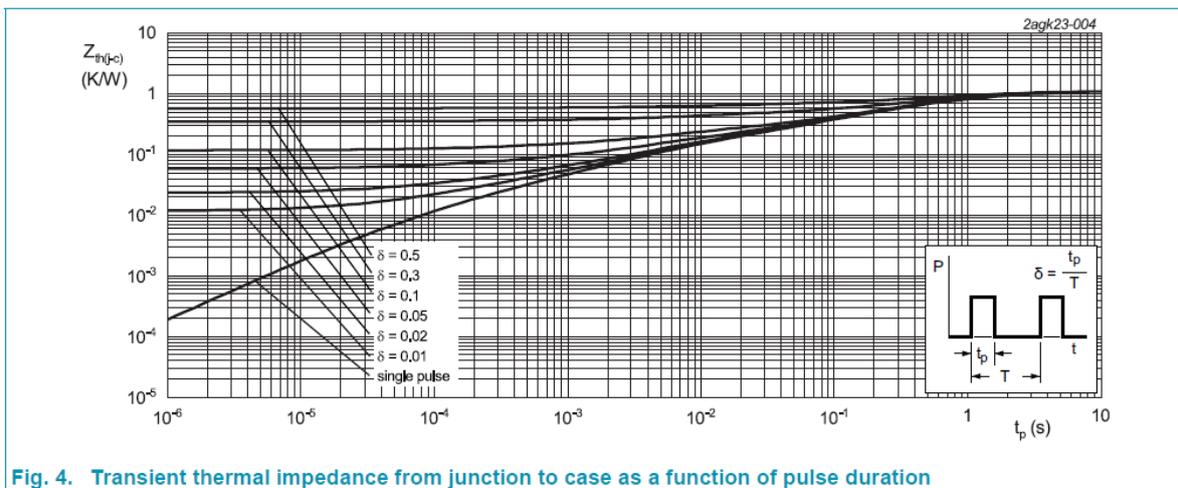


Fig. 4. Transient thermal impedance from junction to case as a function of pulse duration

Fig. 14. Example of transient thermal impedance graphic (WNSC2D10650T)

Although average junction temperature rise may be calculated from the thermal resistance value, the peak junction temperature calculation requires knowledge of the current waveform and the transient thermal impedance curve. This curve in the datasheet is based on rectangular power pulses. Increasing the pulse duration results in higher transient thermal impedance (Z_{th}) until the steady-state, thermal resistance (R_{th}) is reached. If the application operates under transient (pulse) conditions, then Z_{th} instead of R_{th} should be considered since R_{th} is applicable only to steady state, continuous operation. The temperature rise is calculated as the mathematical product of peak dissipation during the pulse by the thermal impedance for the given pulse width.

In practice, a power device must frequently handle composite waveforms rather than a simple rectangular pulse. This type of pulse can be simulated by superimposing several rectangular pulses which have a common time period but with both positive and negative amplitudes. Similarly, a burst of pulses can be treated as a composite waveform. Triangular, trapezoidal, and sinusoidal waveforms can also be approximated by a series of rectangles. This analysis is covered elsewhere.

4.2 Isolation Characteristics

10. Isolation characteristics							
Table 7. Isolation characteristics							
Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$V_{isol(RMS)}$	RMS isolation voltage	from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50\text{ Hz} \leq f \leq 60\text{ Hz}$; $T_n = 25\text{ }^\circ\text{C}$; $RH \leq 65\%$		-	-	2500	V

Fig. 15. Example of Isolation rating (WN5C2D10650X)

The isolation voltage in this example is for the T0220F “full pack” plastic package.

4.3 V_F

Static characteristics							
V_F	forward voltage	$I_F = 10\text{ A}$; $T_j = 25\text{ }^\circ\text{C}$; Fig. 5		-	1.5	1.7	V
		$I_F = 10\text{ A}$; $T_j = 150\text{ }^\circ\text{C}$; Fig. 5		-	1.8	2.2	V
		$I_F = 10\text{ A}$; $T_j = 175\text{ }^\circ\text{C}$; Fig. 5		-	2	2.3	V

Fig. 16. Example of V_F characteristics (WN5C2D10650T)

V_F is the forward voltage for the diode at a specified load current and junction temperature condition. This is the maximum instantaneous forward voltage measured under pulse conditions to avoid excessive power dissipation. It is important to check the specified current and temperature values and whether these are typical or maximum. These values along with V_F / I_F curves at $25\text{ }^\circ\text{C}$ and $T_{j(max)}$, enable fair comparison of device specifications between manufacturers. V_F is lower at smaller current values.

The datasheet V_F / I_F graphic has typical curves measured at the rated operating temperature ($175\text{ }^\circ\text{C}$ in this example) down to $-55\text{ }^\circ\text{C}$. The “maximum” curve is used to calculate the power dissipation for a given average current in most cases.

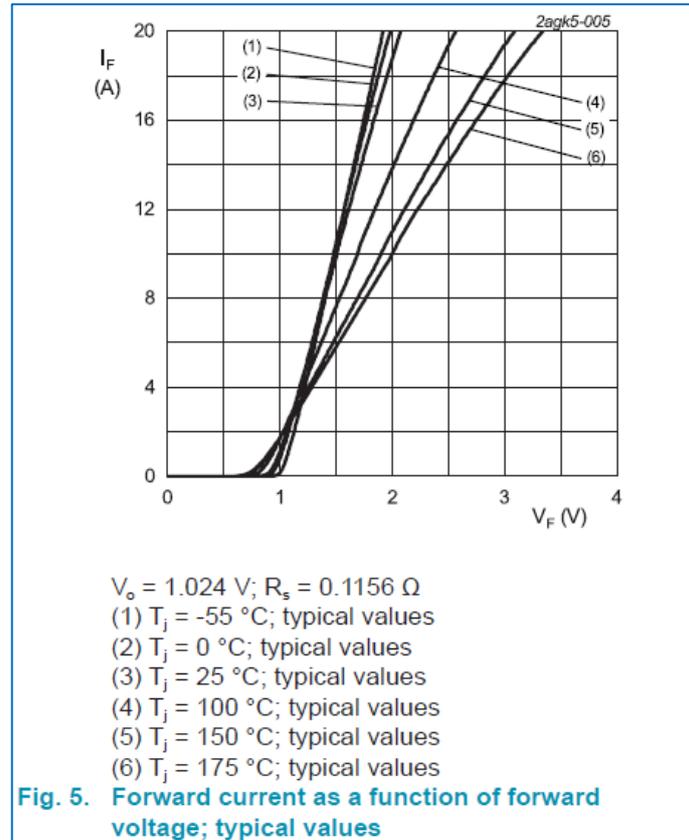


Fig. 17. Example I_F & V_F graphic (WNSC2D10650T)

V_0 is the “knee voltage” and R_s is the slope resistance and their values are usually shown in the V_F / I_F graphic in the datasheet (See Fig. 17). These values are sometimes also shown in the power dissipation graphics.

If values for V_0 and R_s are not given in the datasheet, these can be approximated using the V_F / I_F graphic. Points can be chosen on the $T_{J(\max)}$ curve, connected with a line, and the line extrapolated to yield V_0 and R_s .

The forward characteristic may be approximated by a linear model and the forward voltage is then given by the equation: $V_F = V_0 + I_F \cdot R_s$ and the instantaneous power dissipation is given by $P_F = V_0 \cdot I_F + I_F^2 \cdot R_s$ where I_F is the instantaneous forward current.

It can be shown mathematically that the average forward dissipation for any current waveform is given by the equation, $P_{F(AV)} = V_0 \cdot I_{F(AV)} + I_{F(RMS)}^2 \cdot R_s$, where $I_{F(AV)}$ is the forward average current and $I_{F(RMS)}$ is the RMS value of the forward current.

Therefore, for the diode datasheet, the graph for forward dissipation can be calculated as a function of average current. Square waveforms are assumed, and the graphs usually show the dissipation for various duty cycles. (See Fig. 8).

Similar details for the derivation of V_0 , R_s and power calculations are presented in WAN004, “Triac power and thermal calculations”.

4.4 I_R

I_R	reverse current	$V_R = 650\text{ V}; T_j = 25\text{ }^\circ\text{C}; \text{Fig. 6}$	-	0.5	50	μA
		$V_R = 650\text{ V}; T_j = 175\text{ }^\circ\text{C}; \text{Fig. 6}$	-	25	250	μA

Fig. 18. Example of I_R characteristic (WNSC2D10650T)

I_R is the reverse leakage current with typical and maximum values for maximum operating junction temperature and maximum reverse voltage (see Fig.18).

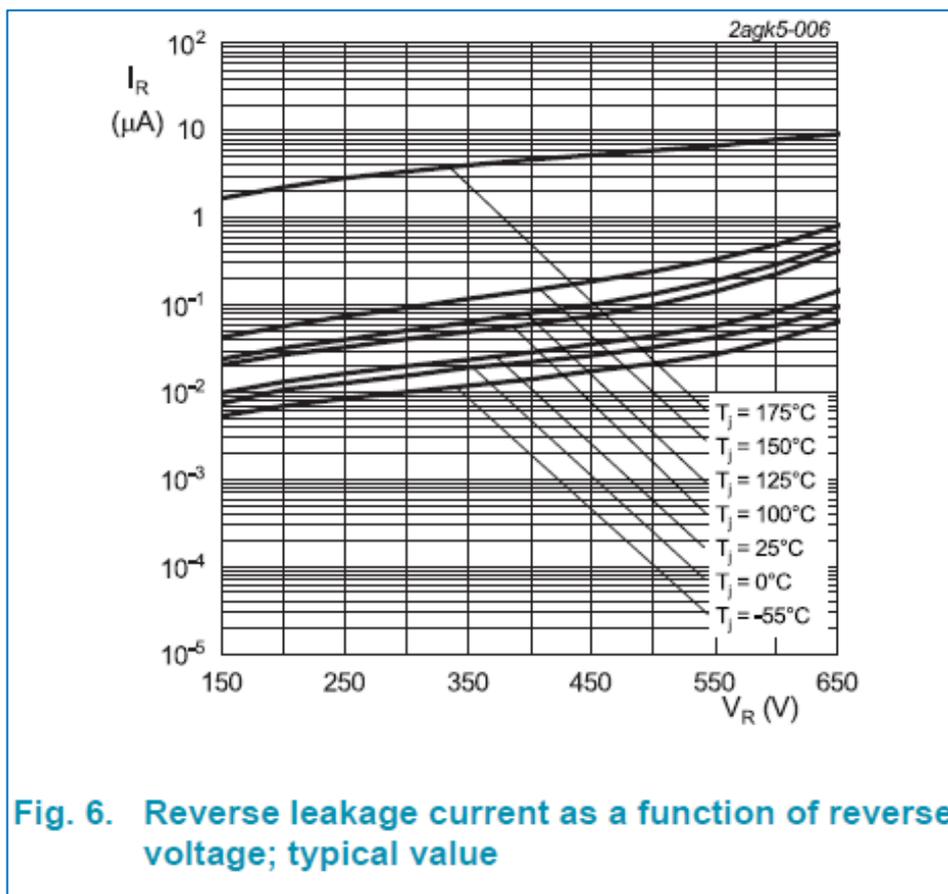


Fig. 19. Example of I_R graphic including junction temperature (WNSC2D10650T)

4.5 Dynamic characteristics: Q_r , C_d & E_{AS}

“Dynamic characteristics” show how diodes cope with fast-changing conditions in a circuit. These are not to be mistakenly understood as limiting values. “Dynamic” means continuous changes in voltage and current.

Dynamic characteristics							
Q_r	recovered charge	$I_F = 10\text{ A}$; $V_R = 400\text{ V}$; $di_F/dt = 500\text{ A}/\mu\text{s}$; $T_j = 25\text{ }^\circ\text{C}$; Fig. 7	-	14	-	nC	
C_d	diode capacitance	$f = 1\text{ MHz}$; $V_R = 1\text{ V}$; $T_j = 25\text{ }^\circ\text{C}$	-	310	-	pF	
		$f = 1\text{ MHz}$; $V_R = 300\text{ V}$; $T_j = 25\text{ }^\circ\text{C}$	-	36	-	pF	
		$f = 1\text{ MHz}$; $V_R = 600\text{ V}$; $T_j = 25\text{ }^\circ\text{C}$	-	32	-	pF	
E_{as}	non-repetitive avalanche energy	$I_R = 5.5\text{ A}$; $T_{j(\text{init})} = 25\text{ }^\circ\text{C}$; $L = 5\text{ mH}$	75	-	-	mJ	

Fig. 20. Example of dynamic characteristics data (WNSC2D10650T)

4.5.1 Recovered charge, Q_r

Silicon Carbide diodes are majority carrier devices and as such do not have significant stored charge that needs to be extracted like bipolar PN diodes after forward conduction. This means that the Q_r curve is flat for all temperatures and so SiC diodes have an excellent temperature-independent switching performance. Bipolar PN diodes whether hyperfast, ultrafast etc., have significant stored charge to be extracted after conducting forward current and so additional reverse recovery characteristics are stated in their datasheets. (see WDN006, “Understanding the diode datasheet”)

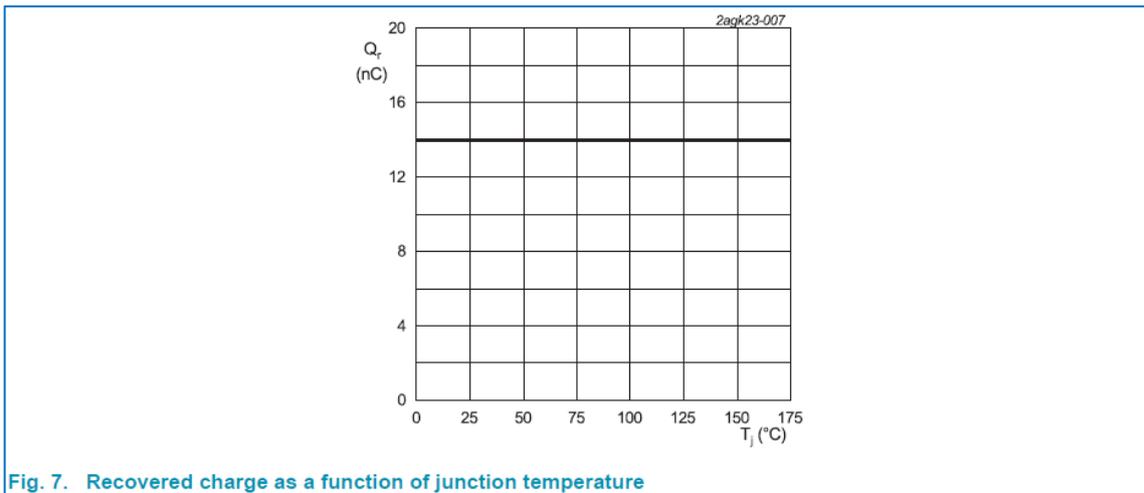


Fig. 7. Recovered charge as a function of junction temperature

Fig. 21. Example of Recovered Charge, Q_r graphic (WNSC2D10650T)

4.5.2 Junction capacitance, C_d

C_d is the junction small signal capacitance of the diode at a specified reverse voltage. Typical values may be given for differing values of V_R or sometimes a graphic may be supplied (see Fig. 20). The higher the current rating of the diode (usually a larger chip), the larger the junction capacitance.

4.5.3 Reverse Avalanche, E_{AS}

This data is helpful in designing circuits which use a diode in free-wheeling mode with an inductive load. As the reverse voltage across a diode is increased a critical value or breakdown voltage is reached which results in an avalanche effect for the leakage current. The reverse energy capability of the diode is specified at 25 °C and this capability may reduce if the diode is at a higher junction temperature just before the avalanche effect begins.

1. Package outline drawing

The datasheet contains a package outline drawing of the device. If a surface mount package is described a soldering pad drawing may also be included.

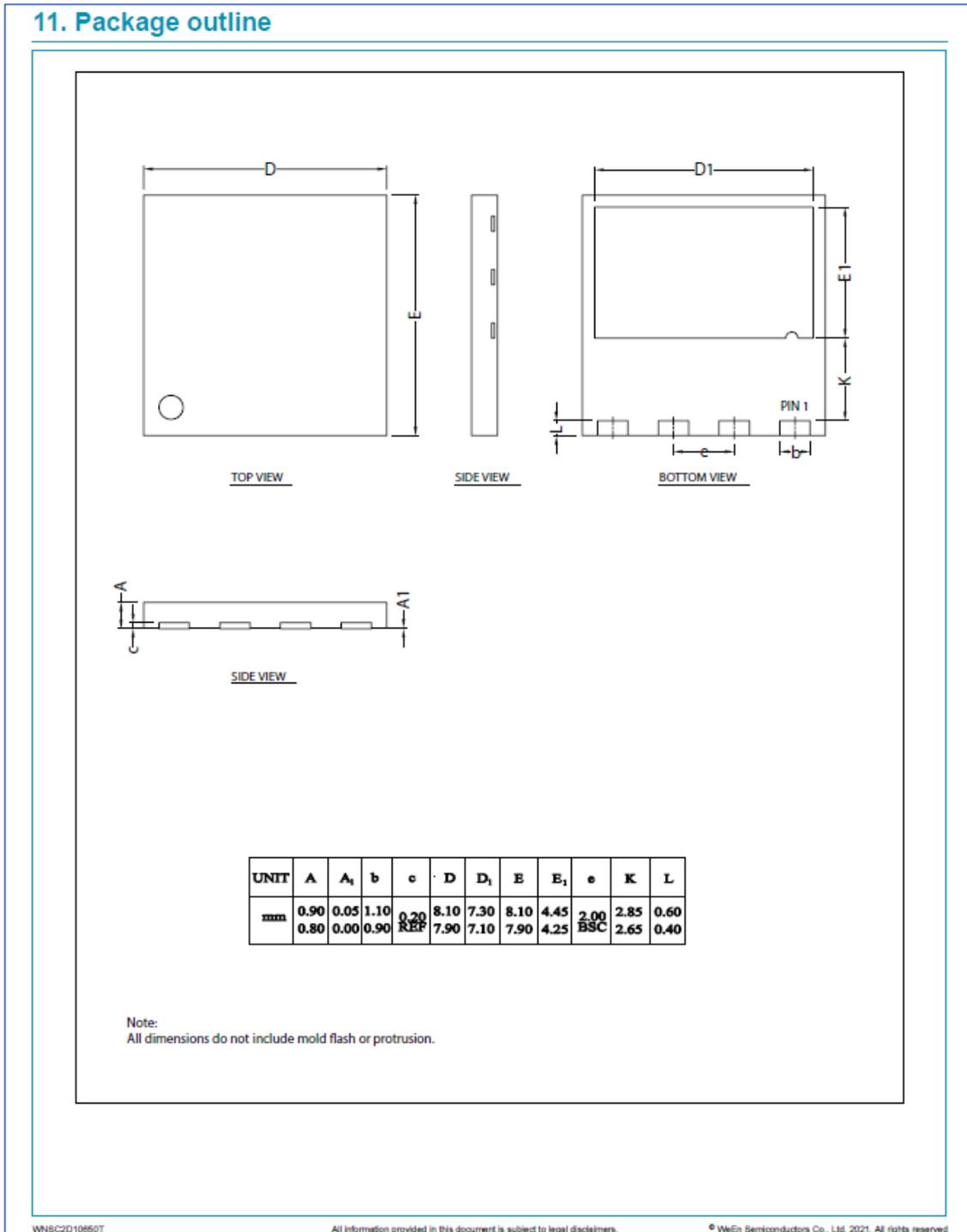


Fig. 22. Example of a “DFN” package outline drawing (WNSC2D10650T)

Revision history

Rev	Date	Description
v.01	20210331	initial version

Contact information

For more information and sales office addresses please visit: <http://www.ween-semi.com>

Legal information

Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. WeEn Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Disclaimers

Limited warranty and liability — Information in this document is believed to be accurate and reliable. However, WeEn Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information. WeEn Semiconductors takes no responsibility for the content in this document if provided by an information source outside of WeEn Semiconductors.

In no event shall WeEn Semiconductors be liable for any indirect, incidental, punitive, special or consequential damages (including - without limitation - lost profits, lost savings, business interruption, costs related to the removal or replacement of any products or rework charges) whether or not such damages are based on tort (including negligence), warranty, breach of contract or any other legal theory.

Notwithstanding any damages that customer might incur for any reason whatsoever, WeEn Semiconductors' aggregate and cumulative liability towards customer for the products described herein shall be limited in accordance with the *Terms and conditions of commercial sale* of WeEn Semiconductors.

Right to make changes — WeEn Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — WeEn Semiconductors products are not designed, authorized or warranted to be suitable for use in life support, life-critical or safety-critical systems or equipment, nor in applications where failure or malfunction of an WeEn Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. WeEn Semiconductors and its suppliers accept no liability for inclusion and/or use of WeEn Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. WeEn Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Customers are responsible for the design and operation of their applications and products using WeEn Semiconductors products, and WeEn Semiconductors accepts no liability for any assistance with applications or customer product design. It is customer's sole responsibility to determine whether the WeEn Semiconductors product is suitable and fit for the customer's applications and products planned, as well as for the planned application and use of customer's third-party customer(s). Customers should provide appropriate design and operating safeguards to minimize the risks associated with their applications and products.

WeEn Semiconductors does not accept any liability related to any default, damage, costs or problem which is based on any weakness or default in the customer's applications or products, or the application or use by customer's third-party customer(s). Customer is responsible for doing all necessary testing for the customer's applications and products using WeEn

Semiconductors products in order to avoid a default of the applications and the products or of the application or use by customer's third-party customer(s). WeEn does not accept any liability in this respect.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from competent authorities.

Evaluation products — This product is provided on an "as is" and "with all faults" basis for evaluation purposes only. WeEn Semiconductors, its affiliates and their suppliers expressly disclaim all warranties, whether express, implied or statutory, including but not limited to the implied warranties of non-infringement, merchantability and fitness for a particular purpose. The entire risk as to the quality, or arising out of the use or performance, of this product remains with customer.

In no event shall WeEn Semiconductors, its affiliates or their suppliers be liable to customer for any special, indirect, consequential, punitive or incidental damages (including without limitation damages for loss of business, business interruption, loss of use, loss of data or information, and the like) arising out the use of or inability to use the product, whether or not based on tort (including negligence), strict liability, breach of contract, breach of warranty or any other theory, even if advised of the possibility of such damages.

Notwithstanding any damages that customer might incur for any reason whatsoever (including without limitation, all damages referenced above and all direct or general damages), the entire liability of WeEn Semiconductors, its affiliates and their suppliers and customer's exclusive remedy for all of the foregoing shall be limited to actual damages incurred by customer based on reasonable reliance up to the greater of the amount actually paid by customer for the product or five dollars (US\$5.00). The foregoing limitations, exclusions and disclaimers shall apply to the maximum extent permitted by applicable law, even if any remedy fails of its essential purpose.

Translations — A non-English (translated) version of a document is for reference only. The English version shall prevail in case of any discrepancy between the translated and English versions.

Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

Contents

1.	Introduction.....	1
2.	Datasheet “Product Profile”	1
3.	Datasheet “Limiting Values”	3
3.1	V_{RRM} , V_{RWM} & V_R	3
3.2	$I_{F(AV)}$ and I_{FRM} [$I_{F(peak)}$]	4
3.3	I_{FSM}	6
3.4	I^2t	6
3.5	T_{stg} and T_j	7
4.	Datasheet characteristics	7
4.1	Thermal characteristics, R_{th} and Z_{th}	7
4.2	Isolation characteristics.....	9
4.3	V_F	9
4.4	I_R	11
4.5	Dynamic characteristics, Q_r , C_d , and E_{AS}	12
4.5.1	Recovered charge, Q_r	12
4.5.2	Junction capacitance, C_d	13
4.5.3	Reverse avalanche energy, E_{as}	13
5.	Package outline drawing	14
	Revision history and contact information	15
	Legal information.....	16
	Definitions	16
	Disclaimers	16
	Trademarks	16
	Contents	17

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section “Legal information.”

© WeEn 2021.

All rights reserved

For more information, please visit: <http://www.ween-semi.com>

Date of release: 31 March 2021

Document identifier: WDN007_Rev01